

## ABSTRACT

METHOD AND INSTALLATION FOR FAST LOCATION  
OF A FAULT IN AN INTEGRATED CIRCUIT

5       The invention relates to a method and an installation for fast location of a fault in an  
integrated circuit. A sequence of NRZ location vectors is created, the abnormal location  
vectors are determined, for which the value of the electrical consumption current at rest  
IDDDQ of the circuit is abnormal, at least one set of images is produced with an abnormal  
location vector, and at least one abnormal vector image is compared with a reference  
10 image.